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AMENDMENTS TO THE CLAIMS:

Please amend the claims as follows:

1. (Cancelled)

2. (Previously presented) The semiconductor device according to claim 51, wherein the

substrate is silicon carbide.

3. (Previously presented) The semiconductor device according to claim 51, wherein said

III-V Nitride semiconductor epitaxial film is formed in contact with a substrate having (11-20)

face.

4. (Cancelled)

5. (Previously presented) The semiconductor device according to claim 51, wherein a

number of group III atoms are equal to a number of nitrogen atoms on a surface of said III-V

Nitride semiconductor epitaxial film.

6-50. (Cancelled)

51. (Previously presented) A semiconductor device comprising a III-V Nitride

semiconductor epitaxial film having 4H-polytype structure formed in contact with a substrate

having 4H-type structure, wherein the III-V Nitride semiconductor epitaxial film is a 4H-AlN

film.

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layer.

52. (New) An optoelectronic device comprising,

a III-V Nitride semiconductor epitaxial film having 4H-polytype structure formed in contact with a substrate having 4-H type structure; and

a waveguide formed on said III-V Nitride semiconductor epitaxial film,
wherein the III-V Nitride semiconductor film is a 4H-AlN film, and
said III-V Nitride semiconductor epitaxial film includes an n-type layer, a p-type layer
and an active layer, said active layer being formed between said n-type layer and said p-type

- 53. (New) The optoelectronic device according to claim 52, wherein a plurality of layers are disposed between said waveguide and said substrate.
- 54. (New) The optoelectronic device according to claim 52, wherein said substrate having 4-H type structure is SiC.
- 55. (New) The optoelectronic device according to claim 52, wherein said III-V Nitride semiconductor epitaxial film is formed on a substrate having (11-20) face.
- 56. (New) The optoelectronic device according to claim 52, wherein a number of group III atoms are equal to a number of nitrogen atoms on a surface of said III-V Nitride semiconductor epitaxial film.
- 57. (New) The optoelectronic device according to claim 52, wherein said waveguide is formed as a straight line perpendicular to either (0001) face or (1-100) face.